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August 2002

## FDH27N50

### 27A, 500V, 0.19 Ohm, N-Channel SMPS Power MOSFET

#### Applications

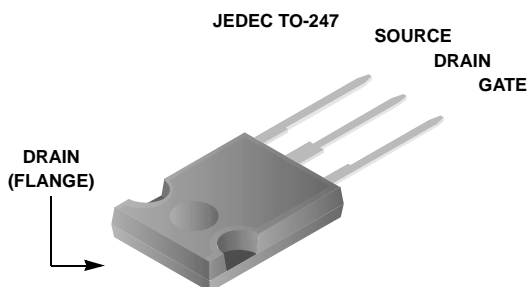
##### Switch Mode Power Supplies(SMPS), such as

- PFC Boost
- Two-Switch Forward Converter
- Single Switch Forward Converter
- Flyback Converter
- Buck Converter
- High Speed Switching

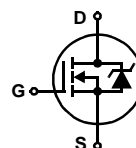
#### Features

- Low Gate Charge Qg results in Simple Drive Requirement
- Improved Gate, Avalanche and High Reapplied dv/dt Ruggedness
- Reduced  $r_{DS(ON)}$
- Reduced Miller Capacitance and Low Input Capacitance
- Improved Switching Speed with Low EMI
- 175°C Rated Junction Temperature

#### Package



#### Symbol



#### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain to Source Voltage	500	V
$V_{GS}$	Gate to Source Voltage	$\pm 30$	V
$I_D$	Drain Current		
	Continuous ( $T_C = 25^\circ\text{C}$ , $V_{GS} = 10\text{V}$ )	27	A
	Continuous ( $T_C = 100^\circ\text{C}$ , $V_{GS} = 10\text{V}$ )	19	A
	Pulsed (Note 1)	108	A
$P_D$	Power dissipation	450	W
	Derate above $25^\circ\text{C}$	3	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature	-55 to 175	$^\circ\text{C}$
	Soldering Temperature for 10 seconds	300 (1.6mm from case)	$^\circ\text{C}$
	Mounting Torque, 8-32 or M3 Screw	10lbf*in (1.1N*m)	

#### Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case	0.33	$^\circ\text{C}/\text{W}$
$R_{\theta CS}$	Thermal Resistance Case to Sink, Flat, Greased Surface	0.24 TYP	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	40	$^\circ\text{C}/\text{W}$

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDH27N50	FDH27N50	TO-247	Tube	-	30

### Electrical Characteristics $T_C = 25^\circ\text{C}$ (unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$B_{VDSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	500	-	-	V
$\Delta B_{VDSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	Reference to $25^\circ\text{C}$ $I_D = 1\text{mA}$	-	0.64	-	$\text{V}/^\circ\text{C}$
$r_{DS(ON)}$	Drain to Source On-Resistance	$V_{GS} = 10\text{V}, I_D = 13.5\text{A}$	-	0.17	0.19	$\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	3.3	4.0	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}$ $V_{GS} = 0\text{V}$	-	-	25	$\mu\text{A}$
		$T_C = 25^\circ\text{C}$	-	-	250	
		$T_C = 150^\circ\text{C}$	-	-	250	
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 30\text{V}$	-	-	$\pm 100$	nA

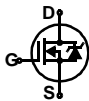
### Dynamics

$g_{fs}$	Forward Transconductance	$V_{DS} = 50\text{V}, I_D = 13.5\text{A}$	11	-	-	S
$Q_g(TOT)$	Total Gate Charge at 10V	$V_{GS} = 10\text{V}$	-	56	67	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 400\text{V}$	-	17	20	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	$I_D = 27\text{A}$	-	18	22	nC
$t_{d(ON)}$	Turn-On Delay Time	$V_{DD} = 250\text{V}$	-	14	-	ns
$t_r$	Rise Time	$I_D = 27\text{A}$	-	54	-	ns
$t_{d(OFF)}$	Turn-Off Delay Time	$R_G = 4.3\Omega$	-	47	-	ns
$t_f$	Fall Time	$R_D = 9.3\Omega$	-	54	-	ns
$C_{ISS}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	3550	-	pF
$C_{OSS}$	Output Capacitance		-	409	-	pF
$C_{RSS}$	Reverse Transfer Capacitance		-	22	-	pF

### Avalanche Characteristics

$E_{AS}$	Single Pulse Avalanche Energy (Note 2)		2552	-	-	mJ
$I_{AR}$	Avalanche Current		-	-	27	A

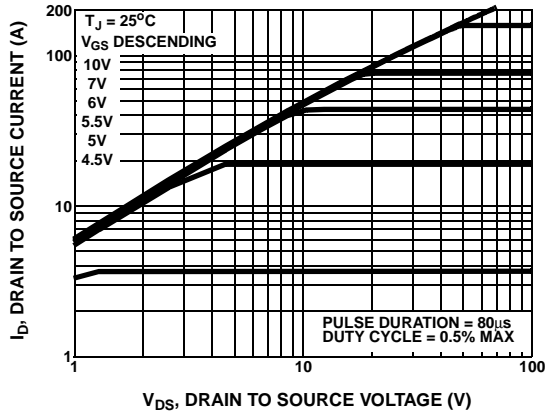
### Drain-Source Diode Characteristics

$I_S$	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode.	-	-	27	A
$I_{SM}$	Pulsed Source Current (Note 1) (Body Diode)		-	-	108	A
$V_{SD}$	Source to Drain Diode Voltage	$I_{SD} = 27\text{A}$	-	0.89	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 27\text{A}, dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	563	714	ns
$Q_{RR}$	Reverse Recovered Charge	$I_{SD} = 27\text{A}, dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	9.2	14	$\mu\text{C}$

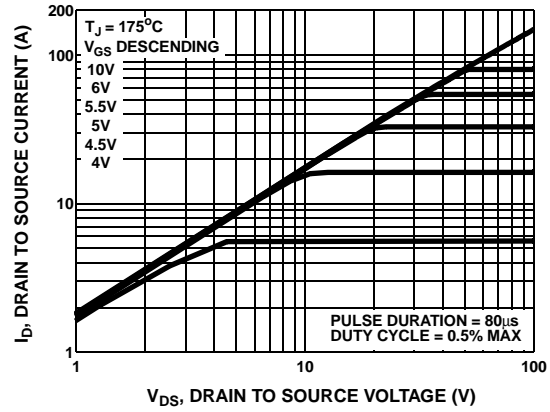
#### Notes:

- 1: Repetitive rating; pulse width limited by maximum junction temperature
- 2: Starting  $T_J = 25^\circ\text{C}$ ,  $L = 7\text{mH}$ ,  $I_{AS} = 27\text{A}$

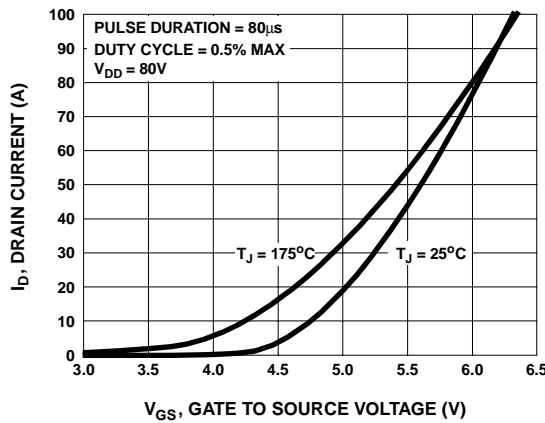
**Typical Characteristics**



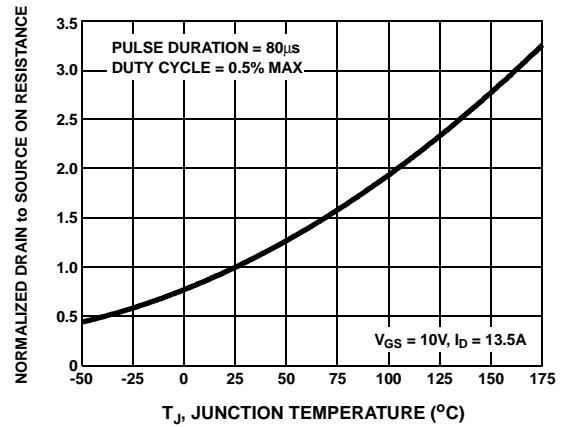
**Figure 1. Output Characteristics**



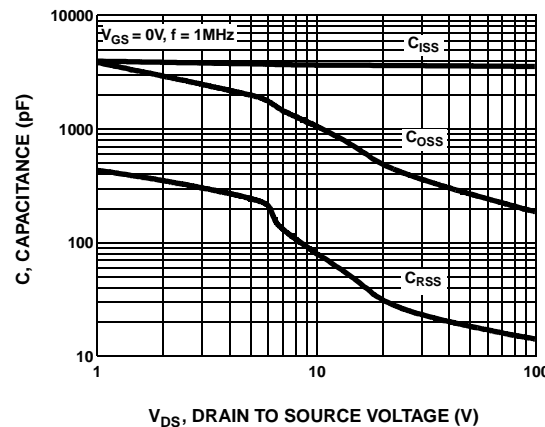
**Figure 2. Output Characteristics**



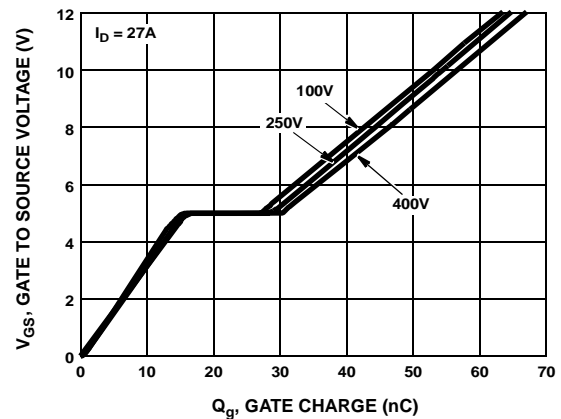
**Figure 3. Transfer Characteristics**



**Figure 4. Normalized Drain To Source On Resistance vs Junction Temperature**

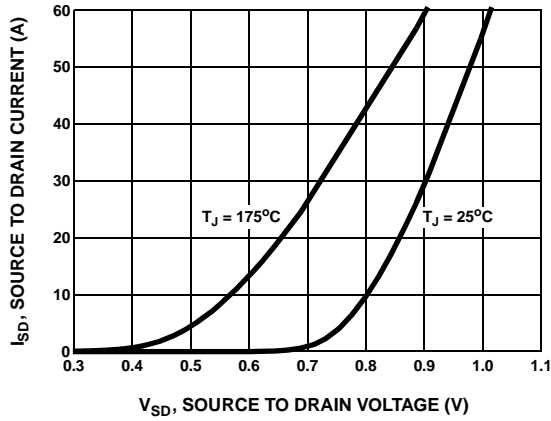


**Figure 5. Capacitance vs Drain To Source Voltage**

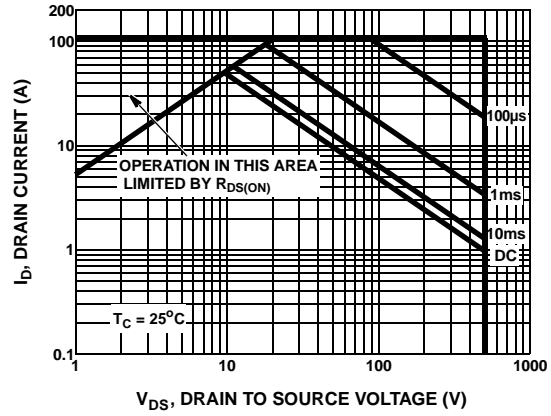


**Figure 6. Gate Charge Waveforms For Constant Gate Current**

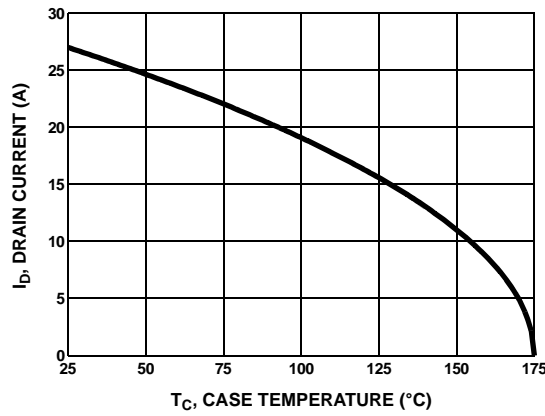
**Typical Characteristics** (Continued)



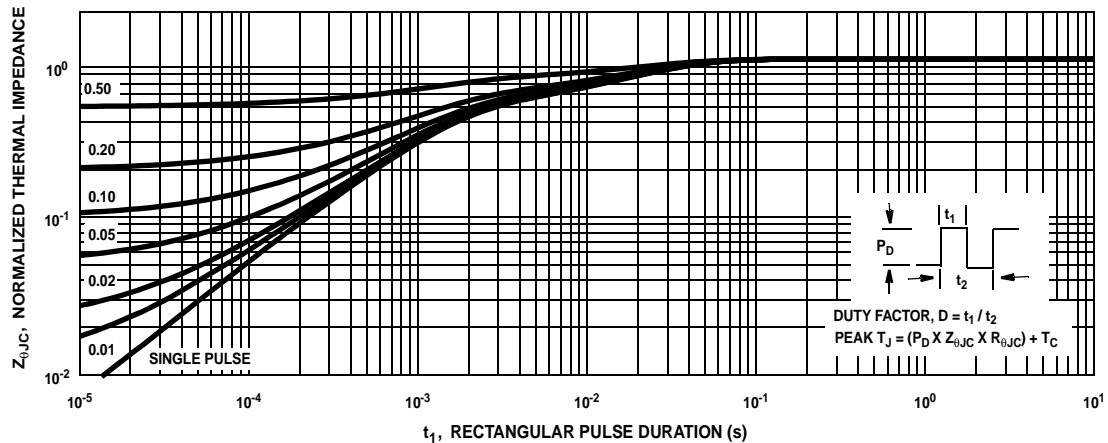
**Figure 7. Body Diode Forward Voltage vs Body Diode Current**



**Figure 8. Maximum Safe Operating Area**



**Figure 9. Maximum Drain Current vs Case Temperature**



**Figure 10. Normalized Maximum Transient Thermal Impedance**

**Test Circuits and Waveforms**

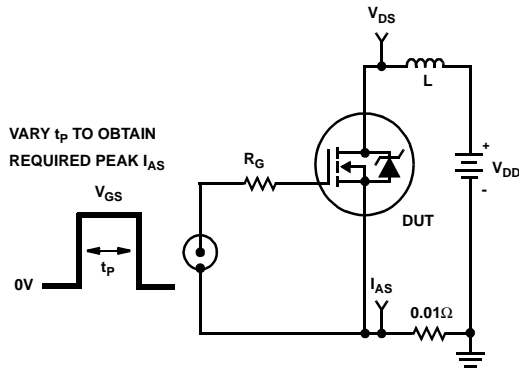


Figure 11. Unclamped Energy Test Circuit

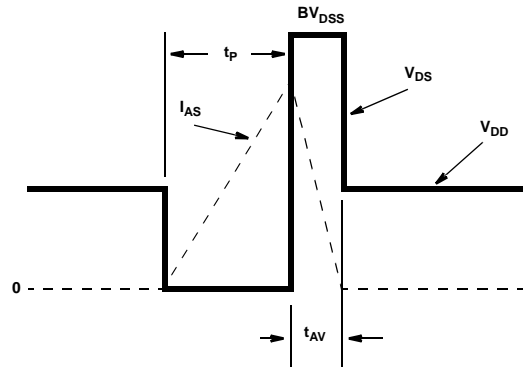


Figure 12. Unclamped Energy Waveforms

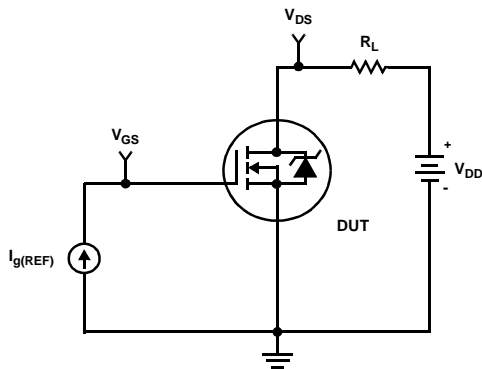


Figure 13. Gate Charge Test Circuit

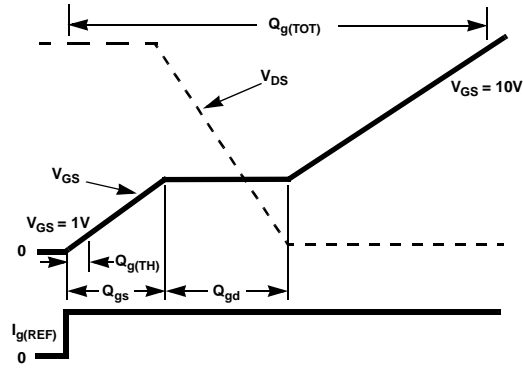


Figure 14. Gate Charge Waveforms

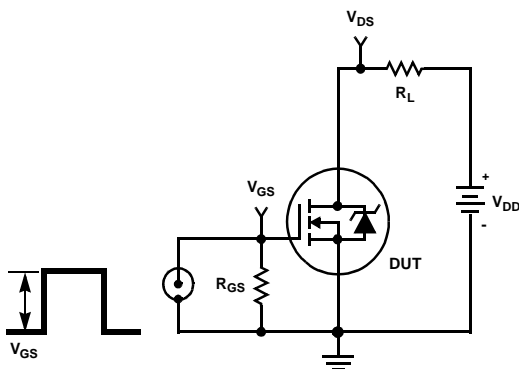


Figure 15. Switching Time Test Circuit

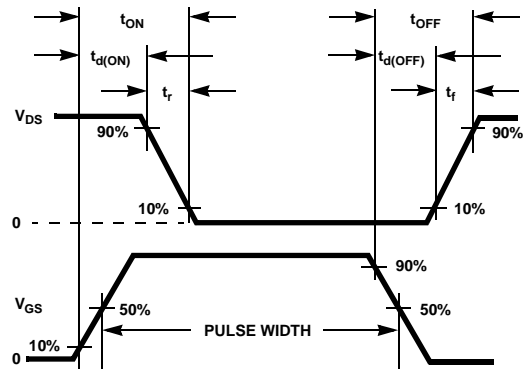


Figure 16. Switching Time Waveform

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